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Application/Control No.	Applica Reexan
10/767,312	JEWET

Applicant(s)/Patent under Reexamination
JEWETT ET AL.
Art Unit

Examiner

David E. Bochna

3679

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
285	141.1	7/11/2006	DB	
	204			
	14			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated the previous search	7/11/2006	DB		